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Transformers and inductors for use in electronic and telecommunication equipment -
Part 389: Measuring methods and test procedures

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CONTENTS

FOREWORD 5
INTRODUCTION 8
1 Scope 9
2 Normative references 9
3 Terms and definitions 10
4 Test procedures 14
4.1 Test and measurement conditions 14
4.1.1 General 14
4.1.2 Measurement uncertainty 14
4.1.3 Alternative test methods 15
4.2 Visual inspection 15
4.2.1 General 15
4.2.2 Safety screen position 15
4.2.3 Quality of joints 15
4.3 Dimensioning and gauging procedure 16
4.4 How to specify tests for electronic transformers 16
4.5 Electrical test procedures 23
4.5.1 Resistance 23
4.5.2 Insulation tests 26
4.5.3 Losses 29
4.5.4 Inductance 38
4.5.5 Unbalance 44
4.5.6 Capacitance 50
4.5.7 Transformation ratio 55
4.5.8 Resonant frequency 60
4.5.9 Signal transfer characteristics 62
4.5.10 Crosstalk 67
4.5.11 Frequency response 68
4.5.12 Voltage-time product rating 75
4.5.13 Total harmonic distortion 77
4.5.14 Voltage regulation 78
4.5.15 Temperature rise 79
4.5.16 Polarity 84
4.5.17 Shielding 87
4.5.18 Noise 90
4.5.19 Inrush-current evaluation and measurement 92
4.5.20 Dynamic CM capacitance of a transformer 93
4.5.21 Tests of the parameter in transformer equivalent circuit 96
4.6 Environmental test procedures 98
4.6.1 General 98
4.6.2 Soldering 99
4.6.3 Robustness of terminations and integral mounting devices 99
4.6.4 Shock 99
4.6.5 Bump 99
4.6.6 Vibration (sinusoidal) 99
4.6.7 Acceleration, steady state 99
4.6.8 Rapid change of temperature (thermal shock in air) 99

4.6.9 Sealing 99
4.6.10 Climatic sequence 100
4.6.11 Damp heat, steady state 100
4.6.12 Dry heat 100
4.6.13 Mould growth 100
4.6.14 Salt mist, cyclic (sodium chloride solution) 100
4.6.15 Sulfur dioxide test for contacts and connections 101
4.6.16 Fire hazard 101
4.6.17 Immersion in cleaning solvents 101
4.7 Endurance test procedures 101
4.7.1 Short-term endurance (load run) 101
4.7.2 Long-term endurance (life test) 102
Annex A (normative) DC resistance test 103
A.1 General 103
A.2 Resistance values from one ohm to megohms 104
A.2.1 General 104
A.2.2 Ammeter and voltmeter method 104
A.2.3 Substitution method 105
A.2.4 Wheatstone bridge 106
A.2.5 Ohmmeter 107
A.3 Digital ohmmeter – Resistance values from under 1 Ω to many kilo-ohms 107
Annex B (normative) Dielectric voltage withstand test 109
Annex C (normative) Induced voltage test 111
C.1 Induced voltage test 111
C.2 General test conditions 111
C.3 General test methods 111
C.4 Induced excitation voltage and frequency 113
C.5 Repeated induced voltage testing 113
C.6 Excitation current 113
Annex D (normative) Corona test 114
D.1 Detection of corona 114
D.2 Analysis of corona 114
D.3 Detection of corona 115
Annex E (normative) Quality factor, Q (Damped oscillation method) 116
E.1 Purpose 116
E.2 Test principle and equipment 116
E.3 Procedure 117
E.4 Calculation 118
E.5 Information to be stated 119
Bibliography 120

Figure 1 – Pulse waveform parameters 12
Figure 2 – Examples of good solder joints 16
Figure 3 – Examples of defective joints 17
Figure 4 – Kelvin double-bridge method test principle 23
Figure 5 – AC resistance test principle 25
Figure 6 – No-load current test schematic 29

Figure 7 – No-load loss test schematic 30
Figure 8 – Circuit diagram of resonant bridge schematic..... 32
Figure 9 – Circuit magnification of basic measurement method schematic 32
Figure 10 – Excitation apparent-power measurements test schematic 33
Figure 11 – Simplified diagram for short-circuit power test 35
Figure 12 – Diagram of efficiency and power factor measurement 36
Figure 13 – Test schematic diagram of LCR tester 38
Figure 14 – Test schematic diagram of impedance analyzer..... 38
Figure 15 – Test schematic diagram of incremental inductor test under DC excitation..... 40
Figure 16 – Different inductances defined by the magnetic flux linkage Ψ as a function of current i 41
Figure 17 – Illustration of energy inductance calculation 42
Figure 18 – Basic circuit for measuring energy inductance..... 43
Figure 19 – Circuit for measuring capacitance unbalance 45
Figure 20 – Circuit for determining common mode rejection ratio..... 46
Figure 21 – Circuit for measuring impedance unbalance 47
Figure 22 – Circuit for determining crosstalk attenuation..... 48
Figure 23 – Measuring techniques for transformer capacitance 51
Figure 24 – Simplified circuit for transformer capacitance measurement..... 51
Figure 25 – Typical graph for determining self-capacitance..... 52
Figure 26 – Test circuit for interwinding capacitance measurement..... 54
Figure 27 – Circuit for determining inter-winding capacitance..... 54
Figure 28 – Diagram of coil voltage and current ratio 56
Figure 29 – Measuring circuit of transformation ratio by voltage and phase displacement..... 58
Figure 30 – Measuring circuit of transformation ratio by current and phase displacement..... 59
Figure 31 – Circuit for determining parallel self-resonant frequency 60
Figure 32 – Circuit for determining resonant frequency of resonant assemblies..... 61
Figure 33 – Measurement of self-resonance 62
Figure 34 – Circuit for determination of insertion loss 63
Figure 35 – Use of two identical transformers when the transformation ratio is not unity and/or a DC bias is required 64
Figure 36 – Illustration of return loss 65
Figure 37 – Basic return loss test circuit 66
Figure 38 – Circuit diagram for measuring the crossover interference between two transformer coils 68
Figure 39 – Impulse waveform measuring circuit..... 69
Figure 40 – Test circuit for frequency response measurements 70
Figure 41 – Test circuit for frequency response measurements with dc current(s) 70
Figure 42 – Alternate method for frequency response measurements..... 72
Figure 43 – Measurement of transformer loss..... 72
Figure 44 – Test circuit for low-level pulse response 74
Figure 45 – Unbiased field and single pulse measurement..... 75
Figure 46 – Biased field and repetitive pulse measurement..... 75

Figure 47 – Non-linearity of magnetizing current 76
Figure 48 – Circuit for measuring harmonic distortion 77
Figure 49 – Voltage regulation test schematic 78
Figure 50 – How to determine R1 79
Figure 51 – Temperature rise measurement circuit by thermo-couple method 81
Figure 52 – Temperature rise measurement circuit by thermal camera method 83
Figure 53 – Phase (polarity) test using voltage measurement 84
Figure 54 – Circuit for bridge measurement of polarity 85
Figure 55 – Series connection method 86
Figure 56 – Typical two winding shielded transformer 87
Figure 57 – Simplified diagram of Figure 56 87
Figure 58 – Helmholtz structure 89
Figure 59 – Dynamic capacitance test of flyback transformers 94
Figure 60 – Full-bridge topology 94
Figure 61 – Dynamic capacitance test of transformer in full-bridge circuit 95
Figure 62 – Equivalent circuit form 1 of non-ideal transformer for magnetic parameter 96
Figure 63 – Equivalent circuit form 2 of non-ideal transformer for magnetic parameter 97
Figure A.1 – Measurement of low resistance 103
Figure A.2 – Ammeter and voltmeter method of resistance measurement 104
Figure A.3 – Measurement of resistance by substitution 105
Figure A.4 – Connections of Wheatstone bridge 106
Figure A.5 – Principle of series ohmmeter 107
Figure A.6 – Digital ohmmeter method of resistance measurement 108
Figure B.1 – Typical high-potential test, showing sec 1 under test 109
Figure B.2 – Typical high-potential test of inductor 109
Figure C.1 – Block diagram of induced voltage surge test 111
Figure D.1 – Typical circuit for corona measurement (circuit 1) 114
Figure D.2 – Typical circuit for corona measurement (circuit 2) 115
Figure E.1 – Damping oscillation method schematic 116
Figure E.2 – Oscilloscope sweep frequency of damping oscillation method schematic 117

Table 1 – Recommended tests and specifications for specific transformer and inductor groups 18
Table 2 – Voltage of dielectric withstanding voltage test 26
Table 3 – Cube dimensions, together with corresponding search coil data 90
Table 4 – Sound-level corrections for noise tests 91
Table 5 – Residual flux density maximum 93

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IEC/IEEE 61007-389 was prepared by IEC technical committee 51: Magnetic components, ferrite and magnetic powder materials, in cooperation with Standards Committee of the IEEE Power Electronics Society, under the IEC/IEEE Dual Logo Agreement between IEC and IEEE. It is an International Standard.

This document is published as an IEC/IEEE Dual Logo standard.

This first edition of IEC/IEEE 61007-389 cancels and replaces IEC 61007:2020 and IEEE 389:2020, which has been technically revised.

This edition includes the following significant technical changes with respect to the previous edition:

a) added the following new test items:
   1) transformer capacitance (in 4.5.6.1);
   2) voltage transformation (VT) ratio (in 4.5.7.3);
   3) thermo-couple method (in 4.5.15.3);
   4) bridge circuit measurement (in 4.5.16.3);
   5) dynamic CM capacitance of a transformer (in 4.5.20);
   6) tests of the parameter in transformer equivalent circuit (in 4.5.21);
b) updated the following test items:
   1) added test purpose: AC resistance (in 4.5.1.2); dielectric withstand voltage test (in 4.5.2.1); effective inductance (in 4.5.4.1); capacitance unbalance (in 4.5.5.1); total harmonic distortion (in 4.5.13);
   2) testing fundamentals and equipment modification: DC winding resistance (in 4.5.1.1); AC resistance (in 4.5.1.2); winding continuity (in 4.5.1.3); excitation apparent-power measurements (in 4.5.3.4); capacitance unbalance (in 4.5.5.1); self-capacitance (distributed capacitance) (in 4.5.6.2); inter-winding capacitance (in 4.5.6.3); inherent self-resonance (in 4.5.8.1); resonant assemblies (in 4.5.8.2); insertion loss (in 4.5.9.1); return loss (in 4.5.9.2); crosstalk (in 4.5.10); pulse characteristics (in 4.5.11.1); transformer response measurements (in 4.5.11.2); total harmonic distortion (in 4.5.13); method utilizing the change in DC resistance of a winding (in 4.5.15.1); method using an additional series-opposing bifilar winding (in 4.5.15.2); safety screens (in 4.5.17.2); magnetic radiation (in 4.5.17.4); acoustic noise (in 4.5.18.1);
   3) procedure modification: dielectric withstand voltage test (in 4.5.2.1); induced voltage test (in 4.5.2.2); capacitance unbalance (in 4.5.5.1);
   4) Information to be stated modification: insulation resistance (in 4.5.2.4); excitation apparent-power measurements (in 4.5.3.4); stray-load losses (in 4.5.3.5); power factor (in 4.5.3.8); inherent self-resonance (in 4.5.8.1); parallel resonance and series resonance (in 4.5.8.3); transformer pulse response (in 4.5.11.3);
c) removed Annex D and Annex F in IEC 61007:2020.

The text of this International Standard is based on the following IEC documents:

Draft	Report on voting
51/1612/FDIS	51/1627/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with the rules given in the ISO/IEC Directives, Part 2, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications/.

A list of all parts in the IEC 61007 series, published under the general title *Transformers and inductors for use in electronic and telecommunication equipment*, can be found on the IEC website.

The IEC Technical Committee and IEEE Technical Committee have decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

– reconfirmed,
– withdrawn, or
– revised.

INTRODUCTION

IEC 61007 describes a number of tests to determine the important parameters and performance characteristics of transformers and inductors used in electronic and telecommunications equipment, aiming to check whether the product meets specific applications and is widely used in industrial manufacturing processes and customer acceptance tests. It includes the test method of electrical testing such as resistance strength, power loss, impedance, inductance value and quality factor, including the test purpose, test procedure and test principle, as well as the reliability test items for electronic transformers and inductors. IEEE Std 389:2020 specifies test and experimental methods applicable to the performance evaluation of electronic transformers and inductors, for the test and evaluation of transformers with lower power ratings (communications, instrumentation, control, small appliance and computer applications). It includes electrical strength, power loss, inductance, impedance and other test items, Kelvin bridge method, impedance bridge method and other measurement methods, but does not include reliability test items and test procedures.

Both documents cover test methods and procedures for electronic transformers and inductors, but they have different emphases and test methods, which bring a lot of inconvenience to users. There is a growing call for establishing an efficient and streamlined universal international standard to meet the needs of developers, customers and the market. Therefore, a proposal for a dual label (IEC/IEEE) standard is formulated to combine IEC 61007 and IEEE Std 389:2020 into one unified new standard.

The structural expression of this document refers to IEC 61007, and on this basis, the expression of test principles, test procedures and test conditions is added for each test item.

This document is a combined and shared standard.

1 Scope

This document describes a number of tests for use in determining the significant parameters and performance characteristics of transformers and inductors for use in electronics and telecommunication equipment. These test methods are designed primarily for transformers and inductors used in all types of electronics applications that can be involved in any specification for such components. Even though these tests could be applied supplementally for other types of transformers, such as those with larger power ratings used in the utility power industry, the tests discussed in this document are not intended to replace the tests in standards for those other transformers.

Some of the tests described are intended for qualifying a product for a specific application, while others are test practices used for manufacturing and customer acceptance testing. The test methods described here include those parameters most commonly used in the electronics transformer and inductor industry: electric strength, resistance, power loss, inductance, impedance, balance, transformation ratio and many others used less frequently.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050 (all parts), *International Electrotechnical Vocabulary (IEV)*, available at https://www.electropedia.org

IEC 60068-1:2013, *Environmental testing - Part 1: General and guidance*

IEC 60068-2-1, *Environmental testing - Part 2-1: Tests - Test A: Cold*

IEC 60068-2-2, *Environmental testing - Part 2-2: Tests - Test B: Dry heat*

IEC 60068-2-6, *Environmental testing - Part 2-6: Tests - Test Fc: Vibration (sinusoidal)*

IEC 60068-2-7, *Basic environmental testing procedures - Part 2-7: Tests - Test Ga and guidance: Acceleration, steady state*

IEC 60068-2-10, *Environmental testing - Part 2-10: Tests - Test J and guidance: Mould growth*

IEC 60068-2-13, *Environmental testing - Part 2-13: Tests - Test M: Low air pressure*

IEC 60068-2-14, *Environmental testing - Part 2-14: Tests - Test N: Change of temperature*

IEC 60068-2-17, *Environmental testing - Part 2-17: Tests - Test Q: Sealing*

IEC 60068-2-20, *Environmental testing - Part 2-20: Tests - Test Ta and Tb: Test methods for solderability and resistance to soldering heat of devices with leads*

IEC 60068-2-21, *Environmental testing - Part 2-21: Tests - Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27, *Environmental testing - Part 2-27: Tests - Test Ea and guidance: Shock*

IEC 60068-2-30, *Environmental testing - Part 2-30: Tests - Test Db: Damp heat, cyclic (12 h + 12 h cycle)*

IEC 60068-2-42, *Environmental testing - Part 2-42: Tests - Test Kc: Sulphur dioxide test for contacts and connections*

IEC 60068-2-45, *Basic environmental testing procedures - Part 2-45: Tests - Test XA and guidance: Immersion in cleaning solvents*

IEC 60068-2-52, *Environmental testing - Part 2-52: Tests - Test Kb: Salt mist, cyclic (sodium chloride solution)*

IEC 60068-2-78, *Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state*

IEC 60695-11-2, *Fire hazard testing - Part 11-2: Test flames - 1 kW pre-mixed flame - Apparatus, confirmatory test arrangement and guidance*

IEC 60695-11-5, *Fire hazard testing - Part 11-5: Test flames - Needle-flame test method - Apparatus, confirmatory test arrangement and guidance*

IEC 61672-1, *Electroacoustics - Sound level meters - Part 1: Specifications*

IEC 62024-2, *High frequency inductive components - Electrical characteristics and measuring methods - Part 2: Rated current of inductors for DC-to-DC converters*

IEC 62044-2, *Cores made of soft magnetic materials - Measuring methods - Part 2: Magnetic properties at low excitation level*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60050 (all parts) and the following apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

– IEC Electropedia: available at https://www.electropedia.org/

– ISO Online browsing platform: available at https://www.iso.org/obp

– *IEEE Standards Dictionary Online*: available at https://dictionary.ieee.org

– Electrical and magnetic terms used in this recommended practice are in accordance with those given in *IEEE Standards Dictionary Online*. Certain parameters and symbols of particular significance in the evaluation of electronics transformers are given where required in the text.

3.1
component
part of a device that cannot be divided into smaller parts without losing their specific functions

Note 1 to entry: The components mentioned in this file refer to transformers or inductors.

3.2
peak working voltage
maximum instantaneous voltage for which the winding insulation is rated under working circuit conditions